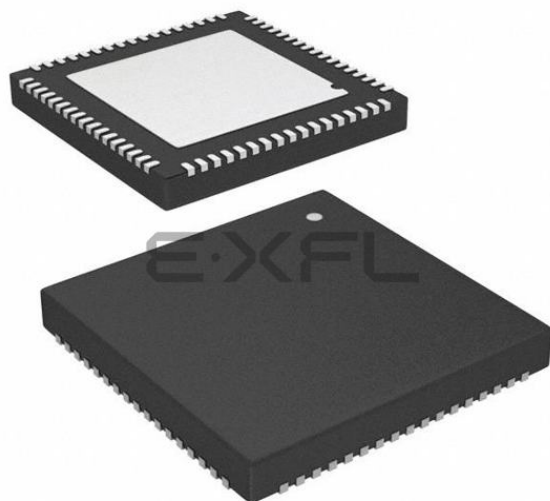




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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	67MHz
Connectivity	I ² C, LINbus, SPI, UART/USART, USB
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	48
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 1x12b; D/A 1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	68-VFQFN Exposed Pad
Supplier Device Package	68-QFN (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c5267lti-lp089

1. Architectural Overview

Introducing the CY8C52LP family of ultra low power, flash Programmable System-on-Chip (PSoC) devices, part of a scalable 8-bit PSoC 3 and 32-bit PSoC 5LP platform. The CY8C52LP family provides configurable blocks of analog, digital, and interconnect circuitry around a CPU subsystem. The combination of a CPU with a flexible analog subsystem, digital subsystem, routing, and I/O enables a high level of integration in a wide variety of consumer, industrial, and medical applications.

Figure 1-1. Simplified Block Diagram

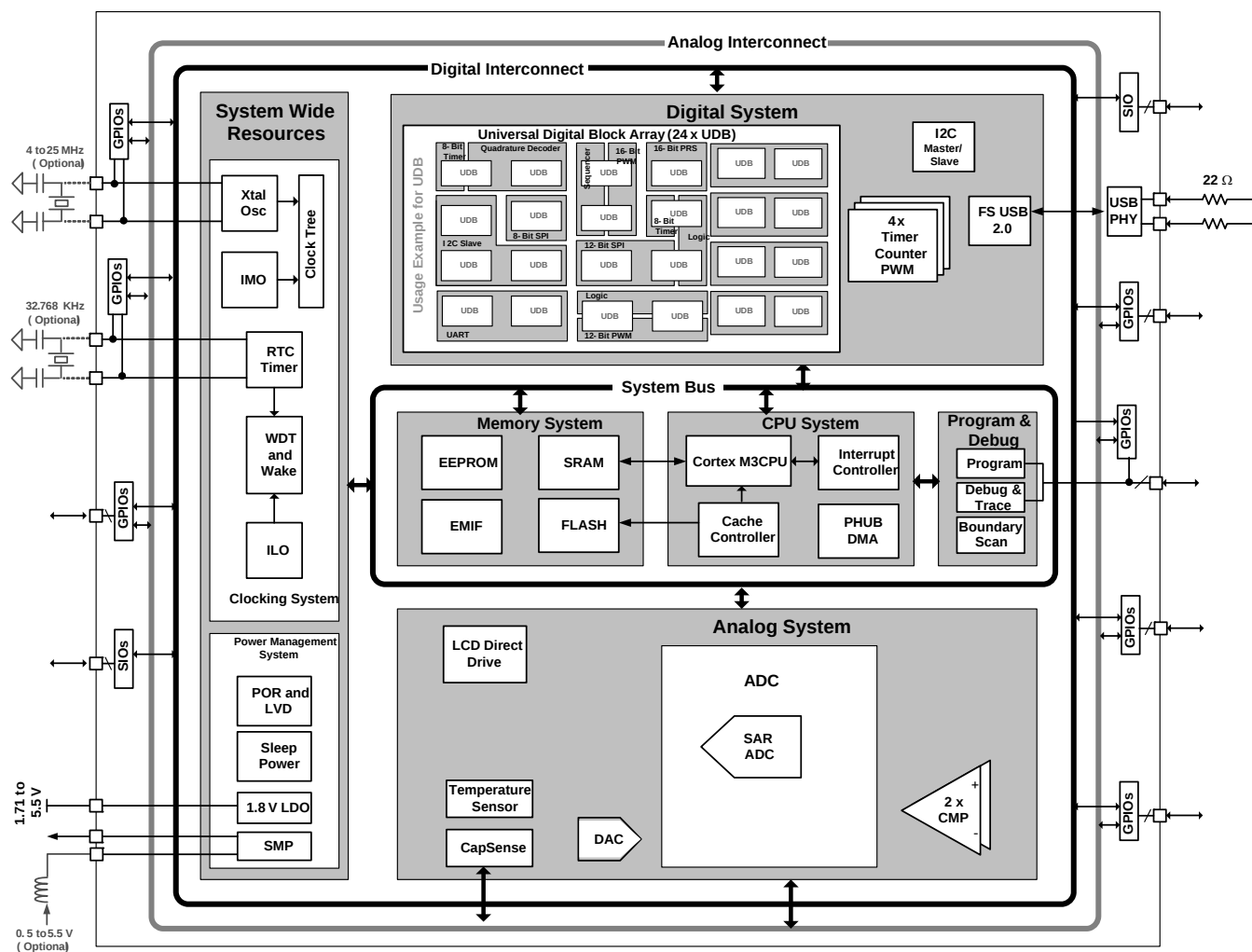


Figure 1-1 illustrates the major components of the CY8C52LP family. They are:

- ARM Cortex-M3 CPU subsystem
- Nonvolatile subsystem
- Programming, debug, and test subsystem
- Inputs and outputs
- Clocking
- Power
- Digital subsystem
- Analog subsystem

PSoC's digital subsystem provides half of its unique configurability. It connects a digital signal from any peripheral to any pin through the digital system interconnect (DSI). It also provides functional flexibility through an array of small, fast, low power UDBs. PSoC Creator provides a library of pre-built and tested standard digital peripherals (UART, SPI, LIN, PRS, CRC, timer, counter, PWM, AND, OR, and so on) that are mapped to the UDB array. You can also easily create a digital circuit using boolean primitives by means of graphical design entry. Each UDB contains programmable array logic (PAL)/programmable logic device (PLD) functionality, together with a small state machine engine to support a wide variety of peripherals.

The details of the PSoC power modes are covered in the “[Power System](#)” section on page 26 of this datasheet.

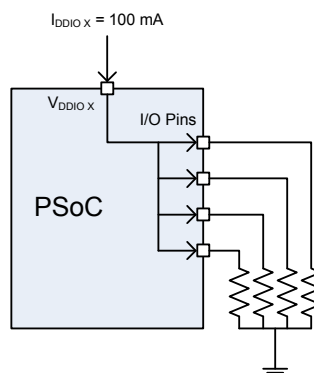
PSoC uses JTAG (4-wire) or SWD (2-wire) interfaces for programming, debug, and test. Using these standard interfaces you can debug or program the PSoC with a variety of hardware solutions from Cypress or third party vendors. The Cortex-M3 debug and trace modules include FPB, DWT, ETM, and ITM. These modules have many features to help solve difficult debug and trace problems. Details of the programming, test, and debugging interfaces are discussed in the “[Programming, Debug Interfaces, Resources](#)” section on page 55 of this datasheet.

2. Pinouts

Each VDDIO pin powers a specific set of I/O pins. (The USBIOs are powered from VDDD.) Using the VDDIO pins, a single PSoC can support multiple voltage levels, reducing the need for off-chip level shifters. The black lines drawn on the pinout diagrams in [Figure 2-3](#) and [Figure 2-4](#), as well as [Table 2-1](#), show the pins that are powered by each VDDIO.

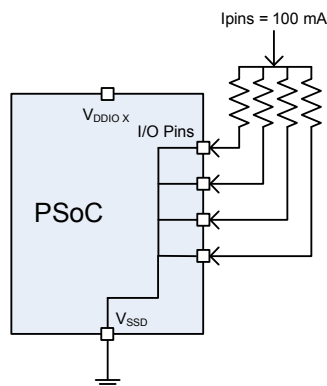
Each VDDIO may source up to 100 mA total to its associated I/O pins, as shown in [Figure 2-1](#).

Figure 2-1. VDDIO Current Limit



Conversely, for the 100-pin and 68-pin devices, the set of I/O pins associated with any VDDIO may sink up to 100 mA total, as shown in [Figure 2-2](#).

Figure 2-2. I/O Pins Current Limit



6.4 I/O System and Routing

PSoC I/Os are extremely flexible. Every GPIO has analog and digital I/O capability. All I/Os have a large number of drive modes, which are set at POR. PSoC also provides up to four individual I/O voltage domains through the VDDIO pins.

There are two types of I/O pins on every device; those with USB provide a third type. Both GPIO and special I/O (SIO) provide similar digital functionality. The primary differences are their analog capability and drive strength. Devices that include USB also provide two USBIO pins that support specific USB functionality as well as limited GPIO capability.

All I/O pins are available for use as digital inputs and outputs for both the CPU and digital peripherals. In addition, all I/O pins can generate an interrupt. The flexible and advanced capabilities of the PSoC I/O, combined with any signal to any pin routability, greatly simplify circuit design and board layout. All GPIO pins can be used for analog input, CapSense^[8], and LCD segment drive, while SIO pins are used for voltages in excess of VDDA and for programmable output voltages.

■ Features supported by both GPIO and SIO:

- User programmable port reset state
- Separate I/O supplies and voltages for up to four groups of I/O
- Digital peripherals use DSI to connect the pins
- Input or output or both for CPU and DMA

- Eight drive modes
- Every pin can be an interrupt source configured as rising edge, falling edge or both edges. If required, level sensitive interrupts are supported through the DSI
- Dedicated port interrupt vector for each port
- Slew rate controlled digital output drive mode
- Access port control and configuration registers on either port basis or pin basis
- Separate port read (PS) and write (DR) data registers to avoid read modify write errors
- Special functionality on a pin by pin basis
- Additional features only provided on the GPIO pins:
 - LCD segment drive on LCD equipped devices
 - CapSense^[8]
 - Analog input and output capability
 - Continuous 100 μ A clamp current capability
 - Standard drive strength down to 1.71 V
- Additional features only provided on SIO pins:
 - Higher drive strength than GPIO
 - Hot swap capability (5 V tolerance at any operating VDD)
 - Programmable and regulated high input and output drive levels down to 1.2 V
 - No analog input, CapSense, or LCD capability
 - Over voltage tolerance up to 5.5 V
 - SIO can act as a general purpose analog comparator

Note

8. GPIOs with opamp outputs are not recommended for use with CapSense.

7. Digital Subsystem

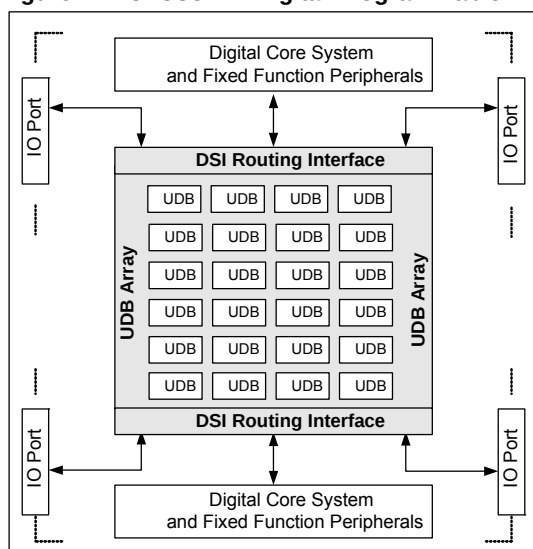
The digital programmable system creates application specific combinations of both standard and advanced digital peripherals and custom logic functions. These peripherals and logic are then interconnected to each other and to any pin on the device, providing a high level of design flexibility and IP security.

The features of the digital programmable system are outlined here to provide an overview of capabilities and architecture. You do not need to interact directly with the programmable digital system at the hardware and register level. PSoC Creator provides a high level schematic capture graphical interface to automatically place and route resources similar to PLDs.

The main components of the digital programmable system are:

- **Universal digital blocks (UDB)** - These form the core functionality of the digital programmable system. UDBs are a collection of uncommitted logic (PLD) and structural logic (Datapath) optimized to create all common embedded peripherals and customized functionality that are application or design specific.
- **Universal digital block array** - UDB blocks are arrayed within a matrix of programmable interconnect. The UDB array structure is homogeneous and allows for flexible mapping of digital functions onto the array. The array supports extensive and flexible routing interconnects between UDBs and the digital system interconnect.
- **Digital system interconnect (DSI)** - Digital signals from UDBs, fixed function peripherals, I/O pins, interrupts, DMA, and other system core signals are attached to the DSI to implement full featured device connectivity. The DSI allows any digital function to any pin or other feature routability when used with the UDB array.

Figure 7-1. CY8C52LP Digital Programmable Architecture



7.1 Example Peripherals

The flexibility of the CY8C52LP family's UDBs and analog blocks allow you to create a wide range of components (peripherals). The most common peripherals were built and characterized by Cypress and are shown in the PSoC Creator component catalog. However, you may also create your own custom components using PSoC Creator. Using PSoC Creator, you may also create their own components for reuse within their organization, for example sensor interfaces, proprietary algorithms, and display interfaces.

The number of components available through PSoC Creator is too numerous to list in the datasheet, and the list is always growing. An example of a component available for use in CY8C52LP family, but, not explicitly called out in this datasheet is the UART component.

7.1.1 Example Digital Components

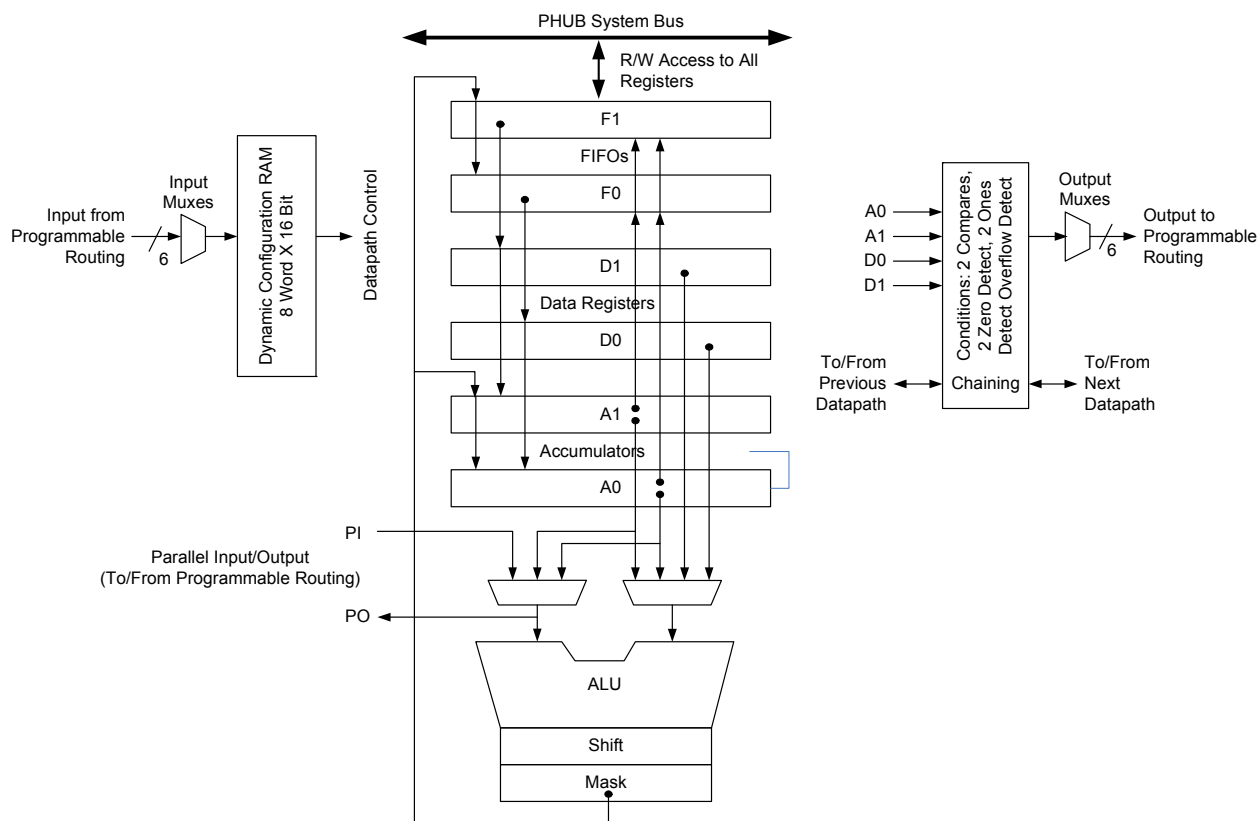
The following is a sample of the digital components available in PSoC Creator for the CY8C52LP family. The exact amount of hardware resources (UDBs, routing, RAM, flash) used by a component varies with the features selected in PSoC Creator for the component.

- **Communications**
 - I²C
 - UART
 - SPI
- **Functions**
 - EMIF
 - PWMs
 - Timers
 - Counters
 -
- **Logic**
 - NOT
 - OR
 - XOR
 - AND

7.1.2 Example Analog Components

The following is a sample of the analog components available in PSoC Creator for the CY8C52LP family. The exact amount of hardware resources (SC/CT blocks, routing, RAM, flash) used by a component varies with the features selected in PSoC Creator for the component.

- **ADC**
 - Successive Approximation (SAR ADC)
- **DACs**
 - Current
 - Voltage
 - PWM
- **Comparators**

Figure 7-4. Datapath Top Level


7.2.2.1 Working Registers

The datapath contains six primary working registers, which are accessed by CPU firmware or DMA during normal operation.

Table 7-1. Working Datapath Registers

Name	Function	Description
A0 and A1	Accumulators	These are sources and sinks for the ALU and also sources for the compares.
D0 and D1	Data Registers	These are sources for the ALU and sources for the compares.
F0 and F1	FIFOs	These are the primary interface to the system bus. They can be a data source for the data registers and accumulators or they can capture data from the accumulators or ALU. Each FIFO is four bytes deep.

7.2.2.2 Dynamic Configuration RAM

Dynamic configuration is the ability to change the datapath function and internal configuration on a cycle-by-cycle basis, under sequencer control. This is implemented using the 8-word × 16-bit configuration RAM, which stores eight unique 16-bit wide configurations. The address input to this RAM controls the sequence, and can be routed from any block connected to the

UDB routing matrix, most typically PLD logic, I/O pins, or from the outputs of this or other datapath blocks.

ALU

The ALU performs eight general purpose functions. They are:

- Increment
- Decrement
- Add
- Subtract
- Logical AND
- Logical OR
- Logical XOR
- Pass, used to pass a value through the ALU to the shift register, mask, or another UDB register

Independent of the ALU operation, these functions are available:

- Shift left
- Shift right
- Nibble swap
- Bitwise OR mask

7.7 I²C

PSoc includes a single fixed-function I²C peripheral. Additional I²C interfaces can be instantiated using Universal Digital Blocks (UDBs) in PSoc Creator, as required.

The I²C peripheral provides a synchronous two-wire interface designed to interface the PSoc device with a two-wire I²C serial communication bus. It is compatible^[12] with I²C Standard-mode, Fast-mode, and Fast-mode Plus devices as defined in the NXP I²C-bus specification and user manual (UM10204). The I²C bus I/O may be implemented with GPIO or SIO in open-drain modes.

To eliminate the need for excessive CPU intervention and overhead, I²C specific support is provided for status detection and generation of framing bits. I²C operates as a slave, a master, or multimaster (Slave and Master)^[12]. In slave mode, the unit always listens for a start condition to begin sending or receiving data. Master mode supplies the ability to generate the Start and Stop conditions and initiate transactions. Multimaster mode provides clock synchronization and arbitration to allow multiple masters on the same bus. If Master mode is enabled and Slave mode is not enabled, the block does not generate interrupts on externally generated Start conditions. I²C interfaces through the DSI routing and allows direct connections to any GPIO or SIO pins.

I²C provides hardware address detect of a 7-bit address without CPU intervention. Additionally the device can wake from low power modes on a 7-bit hardware address match. If wakeup

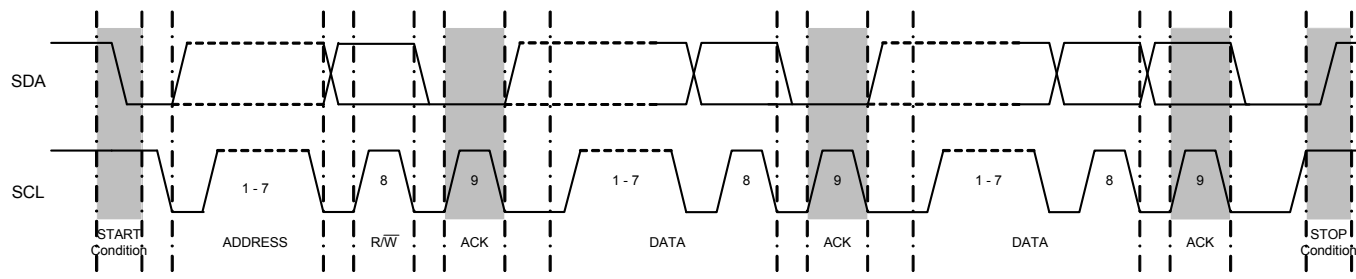
functionality is required, I²C pin connections are limited to one of two specific pairs of SIO pins. See descriptions of SCL and SDA pins in [Pin Descriptions](#) on page 11.

I²C features include:

- Slave and master, transmitter, and receiver operation
- Byte processing for low CPU overhead
- Interrupt or polling CPU interface
- Support for bus speeds up to 1 Mbps
- 7 or 10-bit addressing (10-bit addressing requires firmware support)
- SMBus operation (through firmware support - SMBus supported in hardware in UDBs)
- 7-bit hardware address compare
- Wake from low power modes on address match
- Glitch filtering (active and alternate-active modes only)

Data transfers follow the format shown in [Figure 7-16](#). After the START condition (S), a slave address is sent. This address is 7 bits long followed by an eighth bit which is a data direction bit (R/W) - a 'zero' indicates a transmission (WRITE), a 'one' indicates a request for data (READ). A data transfer is always terminated by a STOP condition (P) generated by the master.

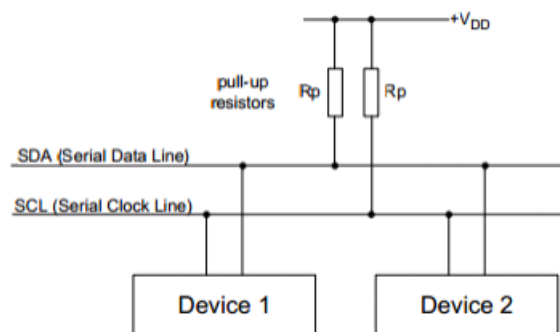
Figure 7-16. I²C Complete Transfer Timing



7.7.1 External Electrical Connections

As [Figure 7-17](#) shows, the I²C bus requires external pull-up resistors (R_P). These resistors are primarily determined by the supply voltage, bus speed, and bus capacitance. For detailed information on how to calculate the optimum pull-up resistor value for your design, we recommend using the UM10204 I²C-bus specification and user manual Rev 6, or newer, available from the NXP website at www.nxp.com.

Figure 7-17. Connection of Devices to the I²C Bus



Notes

11. The I²C peripheral is non-compliant with the NXP I²C specification in the following areas: analog glitch filter, I/O V_{OL}/I_{OL}, I/O hysteresis. The I²C Block has a digital glitch filter (not available in sleep mode). The Fast-mode minimum fall-time specification can be met by setting the I/Os to slow speed mode. See the I/O Electrical Specifications in "Inputs and Outputs" section on page 68 for details.
12. Fixed-block I²C does not support undefined bus conditions, nor does it support Repeated Start in Slave mode. These conditions should be avoided, or the UDB-based I²C component should be used instead.

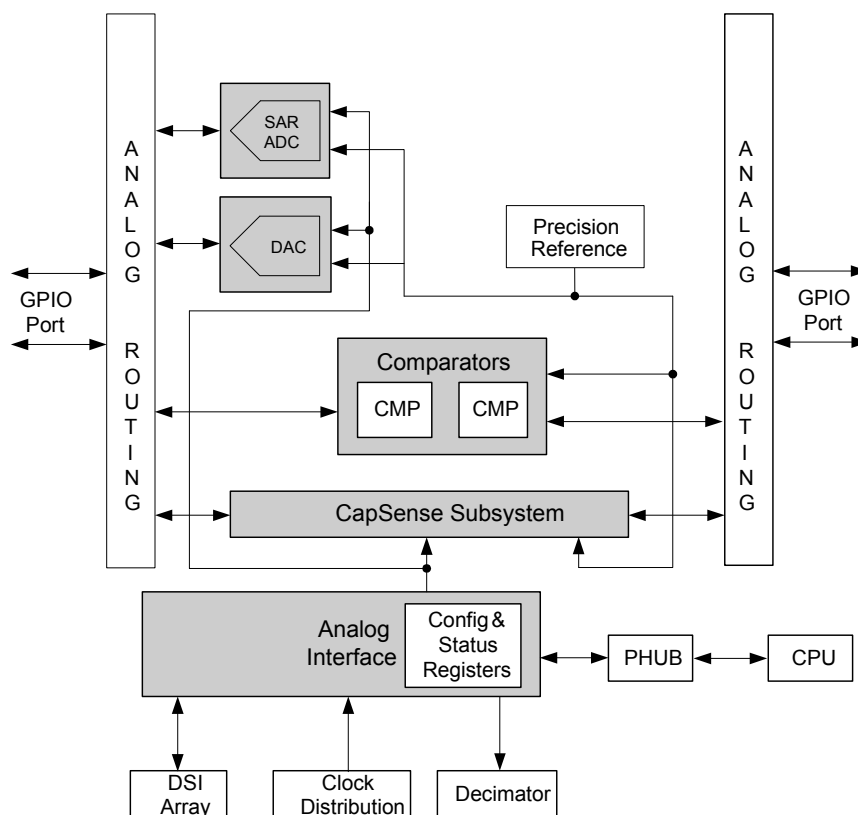
8. Analog Subsystem

The analog programmable system creates application specific combinations of both standard and advanced analog signal processing blocks. These blocks are then interconnected to each other and also to any pin on the device, providing a high level of design flexibility and IP security. The features of the analog subsystem are outlined here to provide an overview of capabilities and architecture.

- Flexible, configurable analog routing architecture provided by analog globals, analog mux bus, and analog local buses

- Successive approximation (SAR) ADC
- One 8-bit DAC that provides either voltage or current output
- Two comparators with optional connection to configurable LUT outputs
- CapSense subsystem to enable capacitive touch sensing
- Precision reference for generating an accurate analog voltage for internal analog blocks

Figure 8-1. Analog Subsystem Block Diagram



The PSoC Creator software program provides a user-friendly interface to configure the analog connections between the GPIO and various analog resources and also connections from one analog resource to another. PSoC Creator also provides component libraries that allow you to configure the various analog blocks to perform application specific functions. The tool also generates API interface libraries that allow you to write firmware that allows the communication between the analog peripheral and CPU/Memory.

8.1 Analog Routing

The PSoC 5LP family of devices has a flexible analog routing architecture that provides the capability to connect GPIOs and different analog blocks, and also route signals between different analog blocks. One of the strong points of this flexible routing architecture is that it allows dynamic routing of input and output connections to the different analog blocks.

For information on how to make pin selections for optimal analog routing, refer to the application note, [AN58304 - PSoC® 3 and PSoC® 5 - Pin Selection for Analog Designs](#).

8.1.1 Features

- Flexible, configurable analog routing architecture
- 16 Analog globals (AG) and two analog mux buses (AMUXBUS) to connect GPIOs and the analog blocks
- Each GPIO is connected to one analog global and one analog mux bus
- 8 Analog local buses (abus) to route signals between the different analog blocks
- Multiplexers and switches for input and output selection of the analog blocks

8.1.2 Functional Description

Analog globals (AGs) and analog mux buses (AMUXBUS) provide analog connectivity between GPIOs and the various analog blocks. There are 16 AGs in the PSoC 5LP family. The analog routing architecture is divided into four quadrants as shown in [Figure 8-2](#). Each quadrant has four analog globals (AGL[0..3], AGL[4..7], AGR[0..3], AGR[4..7]). Each GPIO is connected to the corresponding AG through an analog switch. The analog mux bus is a shared routing resource that connects to every GPIO through an analog switch. There are two AMUXBUS routes in PSoC 5LP, one in the left half (AMUXBUSL) and one in the right half (AMUXBUSR), as shown in [Figure 8-2](#).

Analog local buses (abus) are routing resources located within the analog subsystem and are used to route signals between different analog blocks. There are eight abus routes in PSoC 5LP, four in the left half (abusl [0:3]) and four in the right half (abusr [0:3]) as shown in [Figure 8-2](#). Using the abus saves the analog globals and analog mux buses from being used for interconnecting the analog blocks.

Multiplexers and switches exist on the various buses to direct signals into and out of the analog blocks. A multiplexer can have only one connection on at a time, whereas a switch can have multiple connections on simultaneously. In [Figure 8-2](#), multiplexers are indicated by grayed ovals and switches are indicated by transparent ovals.

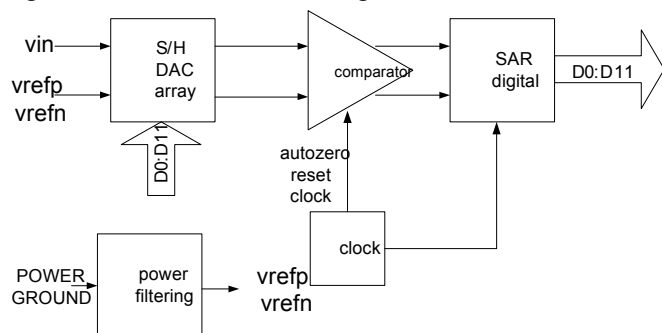
8.2 Successive Approximation ADC

The PSoC 5LP family of devices has a SAR ADC. This ADC is 12-bit at up to 1 Msps, with single-ended or differential inputs, making it useful for a wide variety of sampling and control applications.

8.2.1 Functional Description

In a SAR ADC an analog input signal is sampled and compared with the output of a DAC. A binary search algorithm is applied to the DAC and used to determine the output bits in succession from MSB to LSB. A block diagram of the SAR ADC is shown in Figure 8-3.

Figure 8-3. SAR ADC Block Diagram



The input is connected to the analog globals and muxes. The frequency of the clock is 18 times the sample rate; the clock rate ranges from 1 to 18 MHz.

8.2.2 Conversion Signals

Writing a start bit or assertion of a start of frame (SOF) signal is used to start a conversion. SOF can be used in applications where the sampling period is longer than the conversion time, or when the ADC needs to be synchronized to other hardware. This signal is optional and does not need to be connected if the SAR ADC is running in a continuous mode. A digital clock or UDB output can be used to drive this input. When the SAR is first

powered up or awakened from any of the sleeping modes, there is a power up wait time of 10 μ s before it is ready to start the first conversion.

When the conversion is complete, a status bit is set and the output signal end of frame (EOF) asserts and remains asserted until the value is read by either the DMA controller or the CPU. The EOF signal may be used to trigger an interrupt or a DMA request.

8.2.3 Operational Modes

A ONE_SHOT control bit is used to set the SAR ADC conversion mode to either continuous or one conversion per SOF signal. DMA transfer of continuous samples, without CPU intervention, is supported.

8.3 Comparators

The CY8C52LP family of devices contains two comparators in a device. Comparators have these features:

- Input offset factory trimmed to less than 5 mV
- Rail-to-rail common mode input range (V_{SSA} to V_{DDA})
- Speed and power can be traded off by using one of three modes: fast, slow, or ultra low power
- Comparator outputs can be routed to look up tables to perform simple logic functions and then can also be routed to digital blocks
- The positive input of the comparators may be optionally passed through a low pass filter. Two filters are provided
- Comparator inputs can be connected to GPIO or DAC output

8.3.1 Input and Output Interface

The positive and negative inputs to the comparators come from the analog global buses, the analog mux line, the analog local bus and precision reference through multiplexers. The output from each comparator could be routed to any of the two input LUTs. The output of that LUT is routed to the UDB digital system interface.

Table 11-2. DC Specifications (continued)

Parameter	Description	Conditions	Min	Typ	Max	Units	
I _{DD} ^[21]	Sleep Mode^[22]						
	CPU = OFF RTC = ON (= ECO32K ON, in low-power mode) Sleep timer = ON (= ILO ON at 1 kHz) ^[23] WDT = OFF I ² C Wake = OFF Comparator = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	V _{DD} = V _{DDIO} = 4.5–5.5 V	T = –40 °C	–	1.9	3.1	μA
			T = 25 °C	–	2.4	3.6	
			T = 85 °C	–	5	16	
		V _{DD} = V _{DDIO} = 2.7–3.6 V	T = –40 °C	–	1.7	3.1	
			T = 25 °C	–	2	3.6	
			T = 85 °C	–	4.2	16	
		V _{DD} = V _{DDIO} = 1.71–1.95 V	T = –40 °C	–	1.6	3.1	
			T = 25 °C	–	1.9	3.6	
			T = 85 °C	–	4.2	16	
	Comparator = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF I2C Wake = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	V _{DD} = V _{DDIO} = 2.7–3.6 V ^[24]	T = 25 °C	–	3	4.2	μA
	I2C Wake = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF Comparator = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	V _{DD} = V _{DDIO} = 2.7–3.6 V ^[24]	T = 25 °C	–	1.7	3.6	μA
Hibernate Mode							
	Hibernate mode current All regulators and oscillators off. SRAM retention GPIO interrupts are active Boost = OFF SIO pins in single ended input, unregulated output mode	V _{DD} = V _{DDIO} = 4.5–5.5 V	T = –40 °C	–	0.2	2	μA
			T = 25 °C	–	0.24	2	
			T = 85 °C	–	2.6	15	
		V _{DD} = V _{DDIO} = 2.7–3.6 V	T = –40 °C	–	0.11	2	
			T = 25 °C	–	0.3	2	
			T = 85 °C	–	2	15	
		V _{DD} = V _{DDIO} = 1.71–1.95 V	T = –40 °C	–	0.9	2	
			T = 25 °C	–	0.11	2	
			T = 85 °C	–	1.8	15	
I _{DDAR} ^[24]	Analog current consumption while device is reset	V _{DDA} ≤ 3.6 V		–	0.3	0.6	mA
		V _{DDA} > 3.6 V		–	1.4	3.3	mA
I _{DDDR} ^[24]	Digital current consumption while device is reset	V _{DDD} ≤ 3.6 V		–	1.1	3.1	mA
		V _{DDD} > 3.6 V		–	0.7	3.1	mA
I _{DD_PROG} ^[24]	Current consumption while device programming. Sum of digital, analog, and I/Os: I _{DDD} + I _{DDA} + I _{DDIOX}			–	15	21	mA

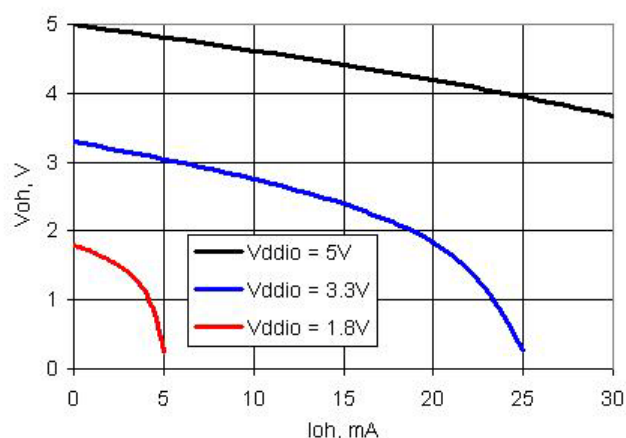
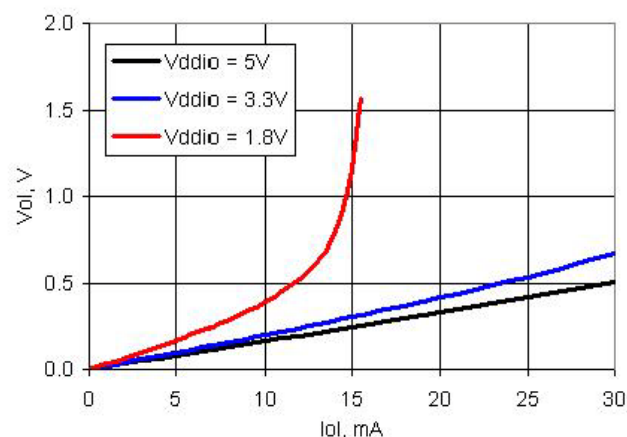
Notes

21. The current consumption of additional peripherals that are implemented only in programmed logic blocks can be found in their respective datasheets, available in PSoC Creator, the integrated design environment. To estimate total current, find CPU current at frequency of interest and add peripheral currents for your particular system from the device datasheet and component datasheets.

22. If V_{CCD} and V_{CCA} are externally regulated, the voltage difference between V_{CCD} and V_{CCA} must be less than 50 mV.

23. Sleep timer generates periodic interrupts to wake up the CPU. This specification applies only to those times that the CPU is off.

24. Based on device characterization (Not production tested). USBIO pins tied to ground (VSSD).

Figure 11-15. GPIO Output High Voltage and Current

Figure 11-16. GPIO Output Low Voltage and Current

Table 11-9. GPIO AC Specifications^[33]

Parameter	Description	Conditions	Min	Typ	Max	Units
TriseF	Rise time in Fast Strong Mode	3.3 V V _{DDIO} Cload = 25 pF	—	—	6	ns
TfallF	Fall time in Fast Strong Mode	3.3 V V _{DDIO} Cload = 25 pF	—	—	6	ns
TriseS	Rise time in Slow Strong Mode	3.3 V V _{DDIO} Cload = 25 pF	—	—	60	ns
TfallS	Fall time in Slow Strong Mode	3.3 V V _{DDIO} Cload = 25 pF	—	—	60	ns
Fgpioout	GPIO output operating frequency					
	2.7 V ≤ V _{DDIO} ≤ 5.5 V, fast strong drive mode	90/10% V _{DDIO} into 25 pF	—	—	33	MHz
	1.71 V ≤ V _{DDIO} < 2.7 V, fast strong drive mode	90/10% V _{DDIO} into 25 pF	—	—	20	MHz
	3.3 V ≤ V _{DDIO} ≤ 5.5 V, slow strong drive mode	90/10% V _{DDIO} into 25 pF	—	—	7	MHz
	1.71 V ≤ V _{DDIO} < 3.3 V, slow strong drive mode	90/10% V _{DDIO} into 25 pF	—	—	3.5	MHz
Fgpioin	GPIO input operating frequency	90/10% V _{DDIO}	—	—	33	MHz

Note

33. Based on device characterization (Not production tested).

Figure 11-27. SAR ADC I_{DD} vs sps, $V_{DDA} = 5$ V, Continuous Sample Mode, External Reference Mode

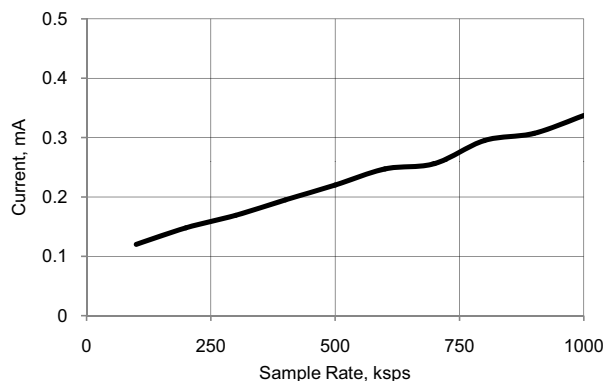


Table 11-20. SAR ADC AC Specifications^[42]

Parameter	Description	Conditions	Min	Typ	Max	Units
A_SAMP_1	Sample rate with external reference bypass cap		–	–	1	Msp
A_SAMP_2	Sample rate with no bypass cap. Reference = V_{DD}		–	–	500	Ksp
A_SAMP_3	Sample rate with no bypass cap. Internal reference		–	–	100	Ksp
	Startup time		–	–	10	μ s
SINAD	Signal-to-noise ratio		68	–	–	dB
THD	Total harmonic distortion		–	–	0.02	%

Figure 11-28. SAR ADC Noise Histogram, 100 kps, Internal Reference No Bypass

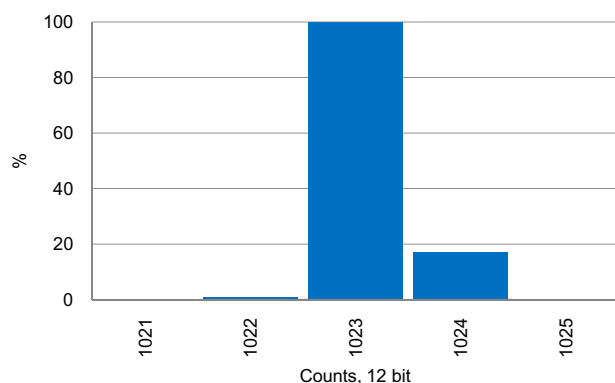
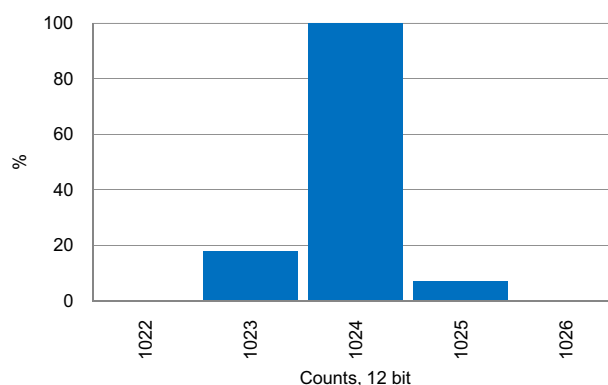


Figure 11-29. SAR ADC Noise Histogram, 1 msp, Internal Reference Bypassed



Note

42. Based on device characterization (Not production tested).

Figure 11-31. IDAC INL vs Input Code, Range = 255 μ A, Source Mode

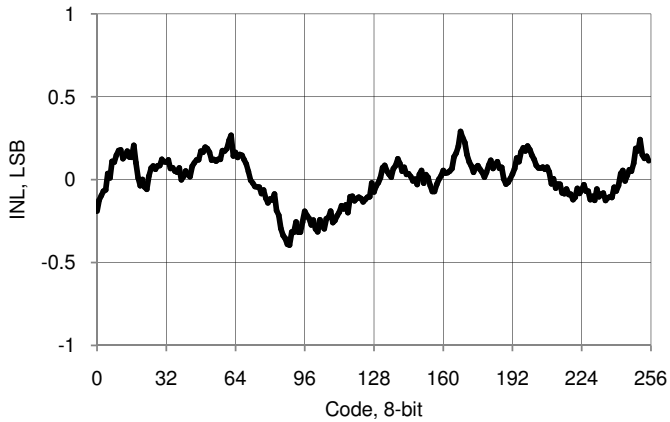


Figure 11-32. IDAC INL vs Input Code, Range = 255 μ A, Sink Mode

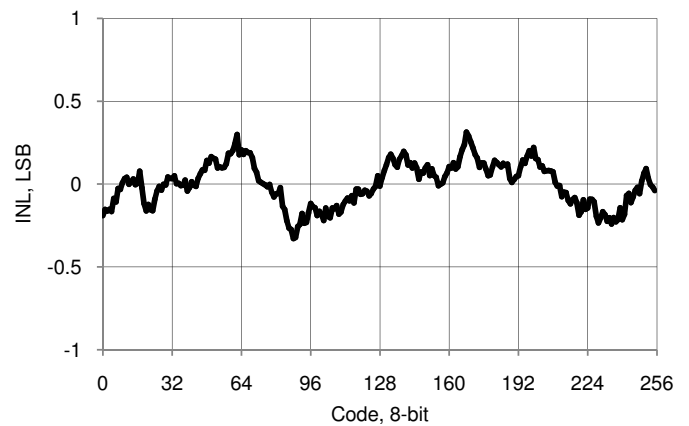


Figure 11-33. IDAC DNL vs Input Code, Range = 255 μ A, Source Mode

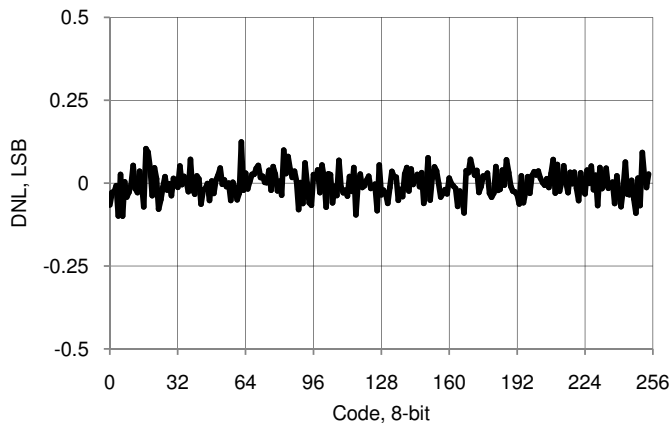


Figure 11-34. IDAC DNL vs Input Code, Range = 255 μ A, Sink Mode

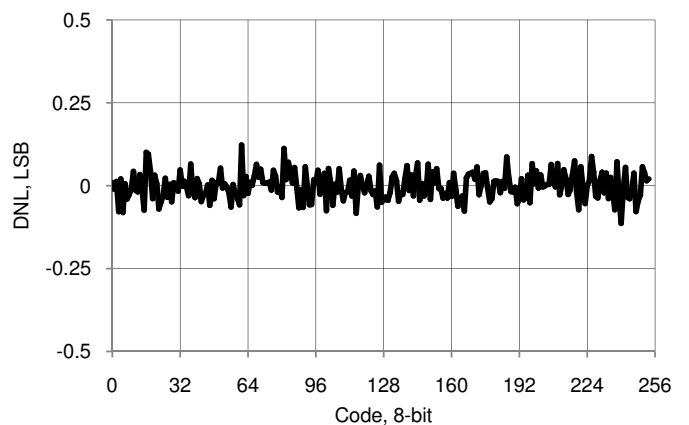


Figure 11-35. IDAC INL vs Temperature, Range = 255 μ A, Fast Mode

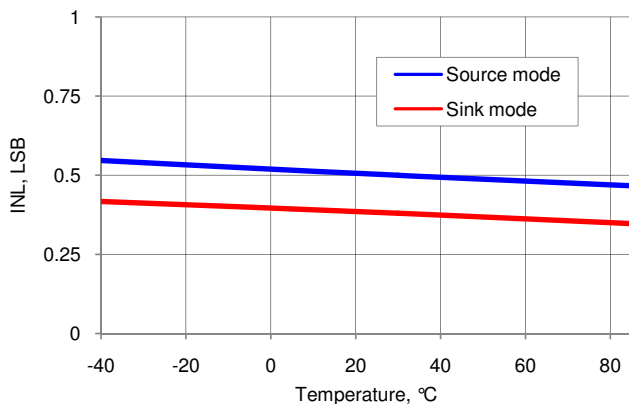


Figure 11-36. IDAC DNL vs Temperature, Range = 255 μ A, Fast Mode

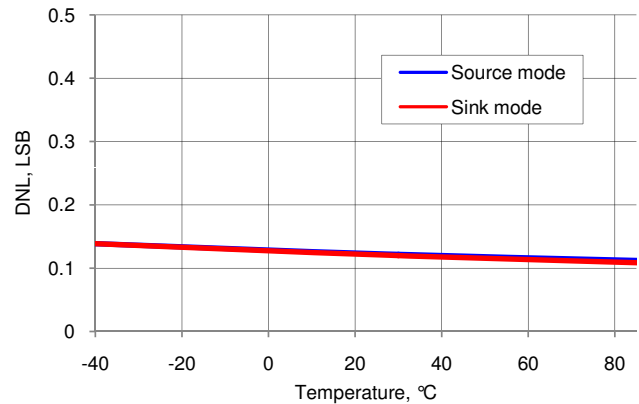
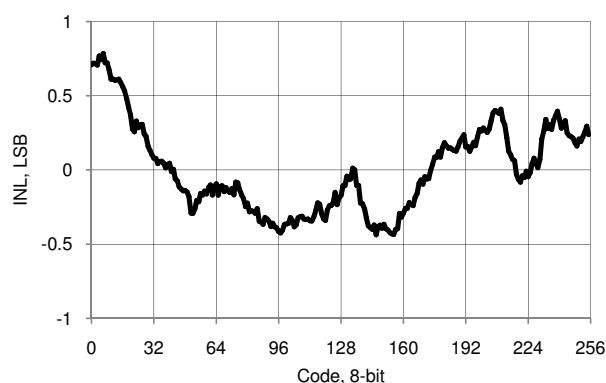
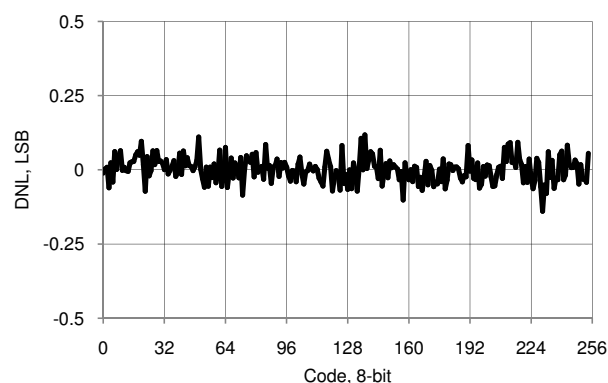
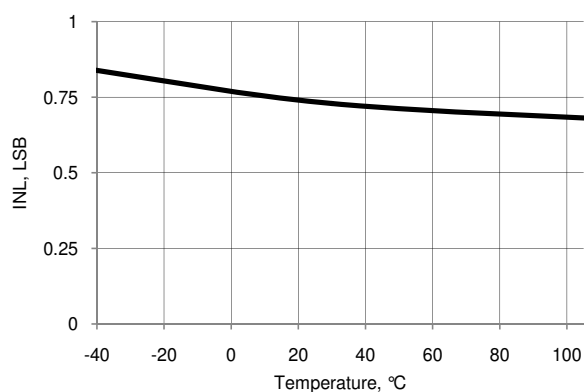
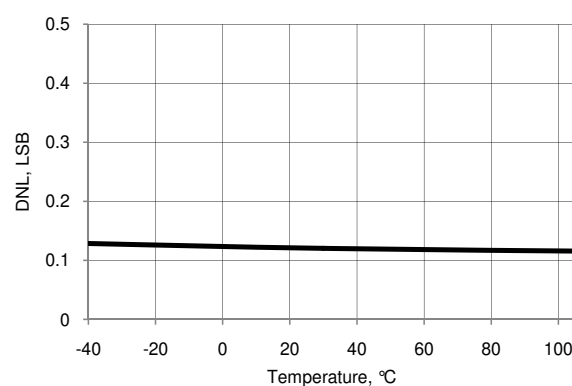


Table 11-27. VDAC DC Specifications (continued)

Parameter	Description	Conditions	Min	Typ	Max	Units
	Monotonicity		–	–	Yes	–
V_{OS}	Zero scale error		–	0	± 0.9	LSB
E_g	Gain error	1 V scale	–	–	± 2.5	%
		4 V scale	–	–	± 2.5	%
TC_{Eg}	Temperature coefficient, gain error	1 V scale	–	–	0.03	%FSR / °C
		4 V scale	–	–	0.03	%FSR / °C
I_{DD}	Operating current ^[52]	Slow mode	–	–	100	μA
		Fast mode	–	–	500	μA

Figure 11-45. VDAC INL vs Input Code, 1 V Mode

Figure 11-46. VDAC DNL vs Input Code, 1 V Mode

Figure 11-47. VDAC INL vs Temperature, 1 V Mode

Figure 11-48. VDAC DNL vs Temperature, 1 V Mode

Note

52. Based on device characterization (Not production tested).

Figure 11-53. VDAC Step Response, Codes 0x40 - 0xC0, 1 V Mode, Fast Mode, $V_{DDA} = 5$ V

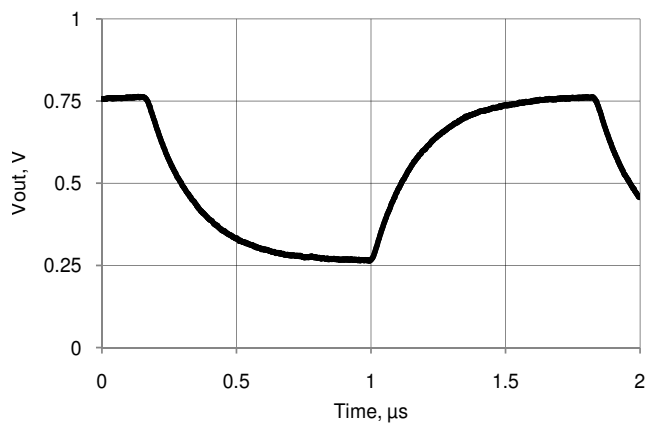


Figure 11-54. VDAC Glitch Response, Codes 0x7F - 0x80, 1 V Mode, Fast Mode, $V_{DDA} = 5$ V

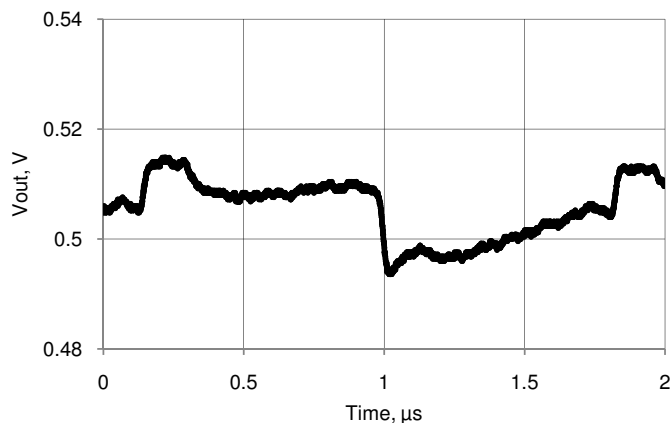


Figure 11-55. VDAC PSRR vs Frequency

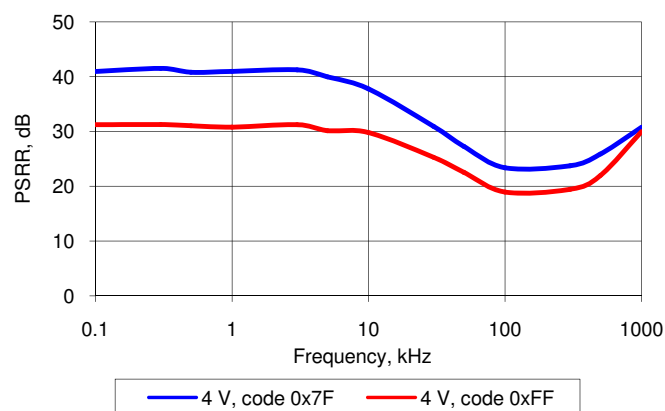
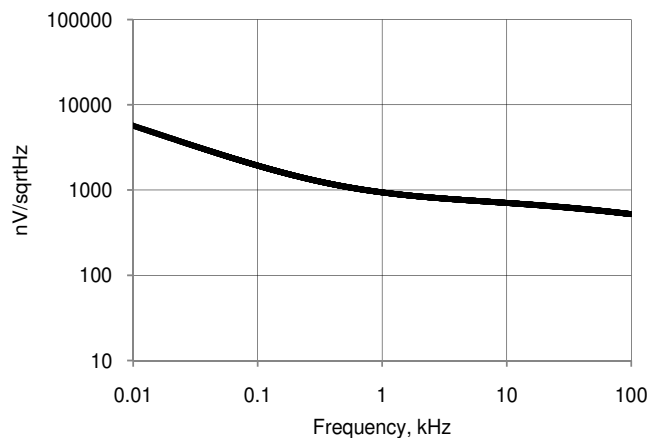


Figure 11-56. VDAC Voltage Noise, 1 V Mode, Fast Mode, $V_{DDA} = 5$ V



11.5.7 Temperature Sensor

Table 11-29. Temperature Sensor Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Temp sensor accuracy	Range: -40 °C to +85 °C	–	±5	–	°C

11.5.8 LCD Direct Drive

Table 11-30. LCD Direct Drive DC Specifications^[54]

Parameter	Description	Conditions	Min	Typ	Max	Units
I_{CC}	LCD Block (no glass)	Device sleep mode with wakeup at 400Hz rate to refresh LCD, bus, clock = 3MHz, Vddio = Vdda = 3V, 8 commons, 16 segments, 1/5 duty cycle, 40 Hz frame rate, no glass connected	–	81	–	μA
I_{CC_SEG}	Current per segment driver	Strong drive mode	–	260	–	μA
V_{BIAS}	LCD bias range (V_{BIAS} refers to the main output voltage(V0) of LCD DAC)	$V_{DDA} \geq 3\text{ V}$ and $V_{DDA} \geq V_{BIAS}$	2	–	5	V
	LCD bias step size	$V_{DDA} \geq 3\text{ V}$ and $V_{DDA} \geq V_{BIAS}$	–	$9.1 \times V_{DDA}$	–	mV
	LCD capacitance per segment/common driver	Drivers may be combined	–	500	5000	pF
	Maximum segment DC offset	$V_{dda} \geq 3\text{V}$ and $V_{dda} \geq V_{bias}$	–	–	20	mV
I_{OUT}	Output drive current per segment driver)	$V_{DDIO} = 5.5\text{V}$, strong drive mode	355	–	710	μA

Table 11-31. LCD Direct Drive AC Specifications^[54]

Parameter	Description	Conditions	Min	Typ	Max	Units
f_{LCD}	LCD frame rate		10	50	150	Hz

Note

54. Based on device characterization (Not production tested).

11.6.5 USB

Table 11-40. USB DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{USB_5}	Device supply (V_{DDD}) for USB operation	USB configured, USB regulator enabled	4.35	–	5.25	V
$V_{USB_3.3}$		USB configured, USB regulator bypassed	3.15	–	3.6	V
V_{USB_3}		USB configured, USB regulator bypassed ^[59]	2.85	–	3.6	V
$I_{USB_Configured}$	Device supply current in device active mode, bus clock and IMO = 24 MHz	$V_{DDD} = 5\text{ V}$, $F_{CPU} = 1.5\text{ MHz}$	–	10	–	mA
		$V_{DDD} = 3.3\text{ V}$, $F_{CPU} = 1.5\text{ MHz}$	–	8	–	mA
$I_{USB_Suspended}$	Device supply current in device sleep mode	$V_{DDD} = 5\text{ V}$, connected to USB host, PICU configured to wake on USB resume signal	–	0.5	–	mA
		$V_{DDD} = 5\text{ V}$, disconnected from USB host	–	0.3	–	mA
		$V_{DDD} = 3.3\text{ V}$, connected to USB host, PICU configured to wake on USB resume signal	–	0.5	–	mA
		$V_{DDD} = 3.3\text{ V}$, disconnected from USB host	–	0.3	–	mA

Note

59. Rise/fall time matching (TR) not guaranteed, see [Table 11-16 on page 75](#).

11.7.5 External Memory Interface

Figure 11-58. Asynchronous Write and Read Cycle Timing, No Wait States

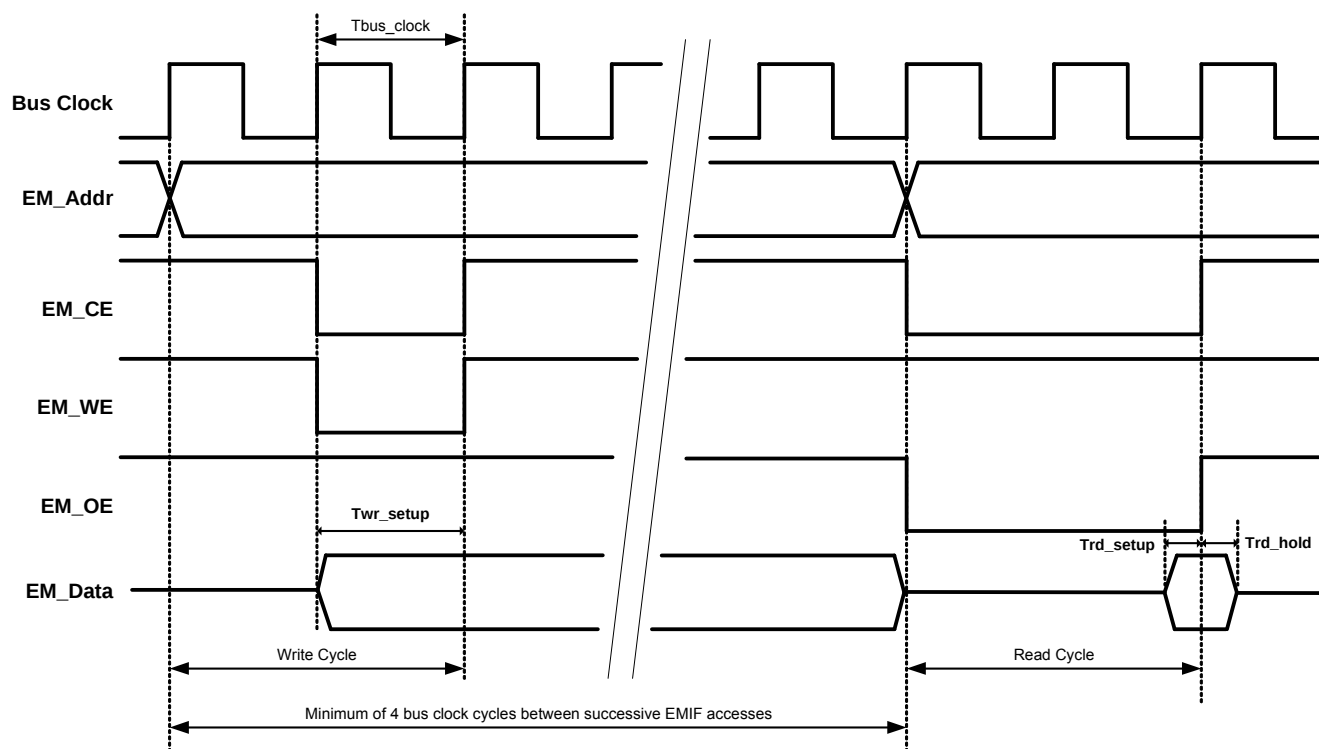


Table 11-50. Asynchronous Write and Read Timing Specifications^[63]

Parameter	Description	Conditions	Min	Typ	Max	Units
Fbus_clock	Bus clock frequency ^[64]		–	–	33	MHz
Tbus_clock	Bus clock period ^[65]		30.3	–	–	ns
Twr_Setup	Time from EM_data valid to rising edge of EM_WE and EM_CE		$T_{bus_clock} - 10$	–	–	ns
Trd_setup	Time that EM_data must be valid before rising edge of EM_OE		5	–	–	ns
Trd_hold	Time that EM_data must be valid after rising edge of EM_OE		5	–	–	ns

Notes

63. Based on device characterization (Not production tested).

64. EMIF signal timings are limited by GPIO frequency limitations. See “GPIO” section on page 68.

65. EMIF output signals are generally synchronized to bus clock, so EMIF signal timings are dependent on bus clock frequency.

11.8 PSoC System Resources

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 85\text{ }^{\circ}\text{C}$ and $T_J \leq 100\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.8.1 POR with Brown Out

For brown out detect in regulated mode, V_{DDD} and V_{DDA} must be $\geq 2.0\text{ V}$. Brown out detect is not available in externally regulated mode.

Table 11-52. Precise Low-Voltage Reset (PRES) with Brown Out DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
PRESR	Rising trip voltage	Factory trim	1.64	–	1.68	V
PRESF	Falling trip voltage		1.62	–	1.66	V

Table 11-53. Power On Reset (POR) with Brown Out AC Specifications^[69]

Parameter	Description	Conditions	Min	Typ	Max	Units
PRES_TR ^[70]	Response time		–	–	0.5	μs
	V_{DDD}/V_{DDA} droop rate	Sleep mode	–	5	–	V/sec

11.8.2 Voltage Monitors

Table 11-54. Voltage Monitors DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
LVI	Trip voltage					
	LVI_A/D_SEL[3:0] = 0000b		1.68	1.73	1.77	V
	LVI_A/D_SEL[3:0] = 0001b		1.89	1.95	2.01	V
	LVI_A/D_SEL[3:0] = 0010b		2.14	2.20	2.27	V
	LVI_A/D_SEL[3:0] = 0011b		2.38	2.45	2.53	V
	LVI_A/D_SEL[3:0] = 0100b		2.62	2.71	2.79	V
	LVI_A/D_SEL[3:0] = 0101b		2.87	2.95	3.04	V
	LVI_A/D_SEL[3:0] = 0110b		3.11	3.21	3.31	V
	LVI_A/D_SEL[3:0] = 0111b		3.35	3.46	3.56	V
	LVI_A/D_SEL[3:0] = 1000b		3.59	3.70	3.81	V
	LVI_A/D_SEL[3:0] = 1001b		3.84	3.95	4.07	V
	LVI_A/D_SEL[3:0] = 1010b		4.08	4.20	4.33	V
	LVI_A/D_SEL[3:0] = 1011b		4.32	4.45	4.59	V
	LVI_A/D_SEL[3:0] = 1100b		4.56	4.70	4.84	V
	LVI_A/D_SEL[3:0] = 1101b		4.83	4.98	5.13	V
	LVI_A/D_SEL[3:0] = 1110b		5.05	5.21	5.37	V
	LVI_A/D_SEL[3:0] = 1111b		5.30	5.47	5.63	V
HVI	Trip voltage		5.57	5.75	5.92	V

Table 11-55. Voltage Monitors AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
LVI_tr ^[70]	Response time		–	–	1	μs

Notes

69. Based on device characterization (Not production tested).

70. This value is calculated, not measured.